

	Type	L #	Hits	Search Text	DBs
1	BRS	L1	1	"6496028".pn.	USPAT
2	BRS	L2	2075	power adj grid	USPAT
3	BRS	L3	688	power adj grid and test\$	USPAT
4	BRS	L4	0	power adj grid and test\$ and ordered adj connections	USPAT
5	BRS	L5	320	power adj grid and test\$ and connections	USPAT
6	BRS	L6	12	power adj grid and test\$ and connections and time adj varying	USPAT
7	BRS	L7	54	power adj grid and test\$ and connections and transient	USPAT
8	BRS	L8	54	power adj grid and test\$ and connections and transient and power	USPAT
9	BRS	L9	11	power adj grid and test\$ and connections and transient and power and measuring	USPAT
10	BRS	L10	1	power adj grid and test\$ and connections and transient and power and measuring and defect\$	USPAT
11	BRS	L11	491	test\$ and connections and transient and power and measuring and defect\$	USPAT
12	BRS	L12	73	test\$ and connections and transient and power and measuring and defect\$ and grid	USPAT
13	BRS	L13	289	test\$ and connections and transient and power and measuring and defect\$ and (grid or array)	USPAT
14	BRS	L14	235	test\$ and connections and transient and power and measuring and defect\$ and (grid or array) and digital	USPAT

	Type	L #	Hits	Search Text	DBs
15	BRS	L15	235	test\$ and connections and transient and power and measuring and defect\$ and (grid or array) and digital and time	USPAT
16	BRS	L16	174	test\$ and connections and transient and power and measuring and defect\$ and (grid or array) and digital and time and varying	USPAT
17	BRS	L17	137	test\$ and connections and transient and power and measuring and defect\$ and (grid or array) and digital and time and varying and logic	USPAT
18	BRS	L18	63	test\$ and connections and transient and power and measuring and defect\$ and (grid or array) and digital and time and varying and logic and vector\$	USPAT
19	BRS	L19	62	test\$ and connections and transient and power and measuring and defect\$ and (grid or array) and digital and time and varying and logic and vector\$ and input\$	USPAT
20	BRS	L20	223	testing and semiconductor and devices and dut and power and defect\$ and time and power	USPAT
21	BRS	L21	58	testing and semiconductor and devices and dut and power and defect\$ and time and varying	USPAT
22	BRS	L22	38	testing and semiconductor and devices and dut and power and defect\$ and time and varying and digital	USPAT

	Type	L #	Hits	Search Text	DBs
23	BRS	L23	28	testing and semiconductor and devices and dut and power and defect\$ and time and varying and digital and logic	USPAT
24	BRS	L24	413	702/117.ccls.	USPAT
25	BRS	L25	715	702/182.ccls.	USPAT
26	BRS	L26	610	702/183.ccls.	USPAT
27	BRS	L27	215	702/184.ccls.	USPAT
28	BRS	L28	358	702/185.ccls.	USPAT
29	BRS	L29	381	702/64.ccls.	USPAT
30	BRS	L30	461	702/188.ccls.	USPAT
31	BRS	L31	1328	438/106.ccls.	USPAT